

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT
(Under 37 CFR 1.97(b) or 1.97(c))

Docket No.
03100275AA

In Re Application Of: **B. Bodermann**

Application No. not yet assigned	Filing Date concurrently	Examiner not yet assigned	Customer No. 30743	Group Art Unit not yet assigned	Confirmation No. not yet assigned
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Title: **METHOD FOR DETERMINING THE REFRACTIVE INDEX DURING INTERFEROMETRIC LENGTH MEASUREMENT AND INTERFEROMETRIC ARRANGEMENT THEREFOR**

Address to:
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

37 CFR 1.97(b)

1. ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.

37 CFR 1.97(c)

2. ☐ The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:

☐ the statement specified in 37 CFR 1.97(e);

OR

☐ the fee set forth in 37 CFR 1.17(p).

1AP20R00010 12 JAN 2006

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Payment of Fee

(Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p))

- ☐ A check in the amount of _____ is attached.
- ☒ The Director is hereby authorized to charge and credit Deposit Account No. 50-2041 as described below.
- ☐ Charge the amount of _____
- ☒ Credit any overpayment.
- ☒ Charge any additional fee required.
- ☐ Payment by credit card. Form PTO-2038 is attached.

WARNING: Information on this form may become public. Credit card information should not be included on this form. Provide credit card information and authorization on PTO-2038.

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Typed or Printed Name of Person Signing Certificate

Certificate of Mailing by First Class Mail

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450" [37 CFR 1.8(a)] on

(Date)

Signature of Person Mailing Correspondence

Typed or Printed Name of Person Mailing Certificate

***This certificate may only be used if paying by deposit account.**


Signature

Dated: January 12, 2006

Marshall M. Curtis
Reg. No. 33,138
Whitham, Curtis, Christofferson & Cook., PC
11491 Sunset Hills Road, Suite 340
Reston, Virginia 20190
703-787-9400
CUSTOMER NUMBER 30743

cc:

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

10/564449 23 JAN 2006

B. Bodermann

Serial No.: not yet assigned

Examiner: not yet assigned

Filing Date: Concurrently

Group Art Unit: not yet assigned

For: METHOD FOR DETERMINING THE REFRACTIVE INDEX
DURING INTERFEROMETRIC LENGTH MEASUREMENT
AND INTERFEROMETRIC ARRANGEMENT THEREFOR

Commissioner for Patents
PO Box 1450
Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 C.F.R. 1.97 through 1.99 and pursuant to applicant's duty of disclosure under 37 C.F.R. 1.56, applicant respectfully brings the following documents, listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application.

These citations do not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application. Please charge any deficiencies in fees and credit any overpayment of fees to attorney's Deposit Account No. 50-2041.

Respectfully submitted,



Marshall M. Curtis

Registration No.: 33,138

703-787-9400

Whitham, Curtis Christofferson & Cook, PC
11491 Sunset Hills Road, Suite 340
Reston, Virginia 20190

703-787-9400

Customer No. 30743

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. 03100275AA		APPLICATION NO. BU/564479 not yet assigned	
				APPLICANT(S) B. Bodermann		12 JAN 2006	
				FILING DATE concurrently			
GROUP ART UNIT not yet assigned							
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6417927	7/2002	de Groot			
		3877813	4/1975	Hayes et al.			
		5838485	11/1998	de Groot et al.			
		5764362	6/1998	Hill et al.			
		5404222	4/1995	Lis			
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/0001086	1/2002	De Groot			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
		2346967	8/2000	United Kingdom			✓
		19727402	2/1998	Germany			✓
		19727404	2/1998	Germany			✓
		WO99/42787	8/1999	International			✓
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
		G. Bonsch et al., "Measurement of the Refractive Index of Air and Comparison with Modified Edlen's Formulae"; Metrologia, 1998 Vol. 35, PP 133-139.					
		B. Boermann et al., "Improved Second Harmonic Two Wavelength Interferometer with Refractive Index Correction without Effect Modulation"; Proc. of SPIE, Vol. 5190, 2003; pp. 339-346.					
EXAMINER				DATE CONSIDERED			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. 03100275AA	10/564449 APPLICATION NO. not yet assigned
	12 JAN 2006 B. Bodermann	
	FILING concurrently	GROUP ART not yet assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	4948254	8/1990	Ishida			
	6014216	1/2000	Zorabedian			
	5412474	5/1995	Reasenberget al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

*	EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	*	EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

EXAMINER	DATE CONSIDERED
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